

Fabrication of crystalline films of 5,5''-bis(4-biphenyl)-2,2':5'2''-terthiophene by vaporized film deposition

NAIST¹, AIST², (M1)Pananus Potisat¹, Sohei Dokiya¹, Fumio Sasaki², Hisao Yanagi¹

E-mail: pananus.potisat.pi4@ms.naist.jp

Thiophene/phenylene co-oligomer, especially 5,5''-bis(4-biphenyl)-2,2':5'2''-terthiophene (BP3T) is one of the most interesting and well recognized light-emitting organic semiconductor and effective gain media for organic laser [1]. Recently, electrically pumped gain-narrowed emission has been reported under ambipolar operation of an organic light-emitting transistor (OLET) with single crystal BP3T [2]. However, it is not easy to handle the OLET fabrication procedure with the single-crystal material under controlled size and thickness. Here, we report an alternative OLET fabrication process by using the vaporized film deposition (VFD) [3], which enable us to construct polycrystalline OLET without breaking the vacuum.

[Experiment] In the VFD method, BP3T was first physically vapor-deposited onto a glass substrate kept at room temperature. Then, the BP3T/glass sample was placed on the heater, faced up against a SiO₂/Si surface, which is spin-coated with fluoropolymer (CYTOP) as a buffer layer, as illustrated in Fig 1(a). The BP3T/glass was heated at

300°C under a vacuum of $\sim 10^{-6}$ mbar, then BP3T was transferred onto the SiO₂/Si surface.

[Result & Discussion] An atomic force microscopy (AFM) image shown in Fig 1(b) indicates that the BP3T film transferred onto the SiO₂/Si surface and form a layer of the polycrystalline structure while the source film of BP3T on glass is composed of randomly pile granules. The size and thickness of the layered crystallite are averagely 5 μm and 150 nm, respectively. Their fluorescence microscopy suggests that the BP3T molecules orient standing in the layered crystallites which is a favorable configuration for carrier transportation in OLET and light-amplification in planar crystal cavity. OLET fabrication and measurement under all vacuum operation will be presented in the poster

References

- [1] T. Hiramatsu, N. Matsuoka, H. Yanangi, F. Sasaki, S. Hotta, *phys. stat. sol.* **6**, 338-341 (2009)
- [2] H. Shimotani, T. Kanagasekaran, K. Kasai, S. Onuki, K. Tanigaki, *The 78th Annual meeting of JSAP*, 7a-A203-1 (2017)
- [3] S. Dokiya, F. Sasaki, H. Yanagi, *J. of Cryst. Growth*, **468**, 792 (2017)

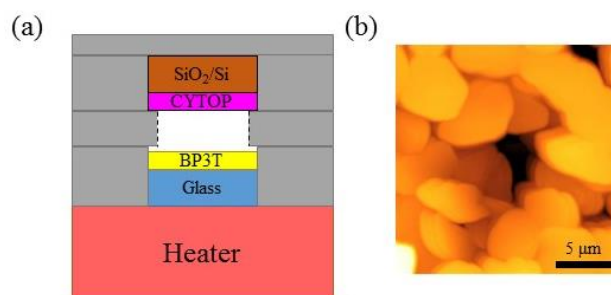


Fig 1 (a) VFD set-up, and (b) AFM image of polycrystalline BP3T film transferred onto SiO₂/Si surface